MSKSEMI 美森科













FSD

1/5

TSS

MOV

GDT

PIFD

AO4430

Product specification





General Features

- 30 V, 16A, RDS(ON)=4.8mΩ@VGS = 10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Application

- Notebook
- Load Switch
- LED applications
- Hand-Held Device

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
SOP-8	G	MSKSEMI 4430 MS30N



Absolute Maximum Ratings (TA=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
	Drain-Source Voltage		
V _{DS}	Brain course voltage	30	V
V _{GS}	Gate-Source Voltage	±20	V
l-	Drain Current – Continuous (T _C =250)	16	А
lo	Drain Current – Continuous (T _C =100C)	9.5	А
I _{DM}	Drain Current – Pulsed ¹	60	А
D ₌	Power Dissipation (T _C =25C)	4	W
P_D	Power Dissipation – Derate above 250	0.032	W/ C
T _{STG}	Storage Temperature Range	-55 to 150	С
TJ	Operating Junction Temperature Range	-55 to 150	С

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient	· 	85	C/ W
Пела			85	
R _{eJC}	Thermal Resistance Junction to Case		31	C/ W

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30	-		V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 250 , I _D =1mA		0.04		V/ C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =30V , V _{GS} =0V , T _J =250			1	uA
1055		V _{DS} =24V , V _{GS} =0V , T _J =1250			10	uA
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA



On Characteristics

R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V , I _D =6A		4.8	8	mΩ
TOS(ON)		V _{GS} =4.5V , I _D =3A		7.5	14	Ω_{m}
V _{GS(th)}	Gate Threshold Voltage		1.2	1.5	2.5	V
	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =250uA				
$\triangle V_{GS(th)}$				-4		mV/ C
gfs	Forward Transconductance	V _{DS} =10V , I _D =10A		18		S

Dynamic and switching Characteristics

Dynamic	and Switching	Characteristics		
Qg	Total Gate Charge ^{2, 3}		 7.5	
Qgs	Gate-Source Charge ^{2,3}	V _{DS} =15V , V _{GS} =4.5V , I _D =10A	 1.3	 nC
Q _{gd}	Gate-Drain Charge ^{2,3}		 4.5	
T _{d(on)}	Turn-On Delay Time ^{2, 3}		 4.8	
Tr	Rise Time ^{2, 3}	V_{DD} =15V , V_{GS} =10V , R_{G} =3.3 Ω	 12.5	 ns
T _{d(off)}	Turn-Off Delay Time ^{2, 3}	I _D =15A	 27.6	
T _f	Fall Time ^{2,3}		 8.2	
Ciss	Input Capacitance		 750	
Coss	Output Capacitance	V _{DS} =25V , V _{GS} =0V , F=1MHz	 150	 pF
C _{rss}	Reverse Transfer Capac	tance	 110	
Rg	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	 2.7	 Ω

Drain- Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V _G =V _D =0V , Force Current			16	Α
I _{SM}	Pulsed Source Current	VG-VD-0V , I GICE Current			32	А
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =1A , T _J =250			1.2	V

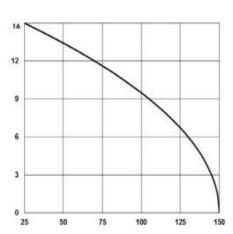
Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width $\leq 300\,\mathrm{us}$, duty cycle $\leq 2\%$.
- 3. Essentially independent of operating temperature.

In , Continuous Drain Current (A)

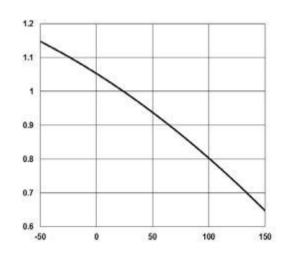
Normalized Gate Threshold Voltage (V)

Normalized Thermal Response (Reuc)



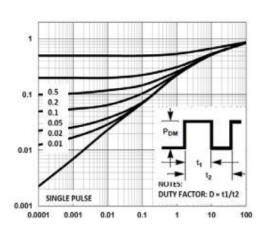
 T_C , Case Temperature (°C)

Fig. 1 Continuous Drain Current vs. Tc



 T_J , Junction Temperature (°C)

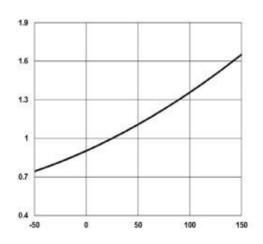
Fig. 3 Normalized V_{th} vs. T_J



Square Wave Pulse Duration (s)

Fig. 5 Normalized Transient Impedance

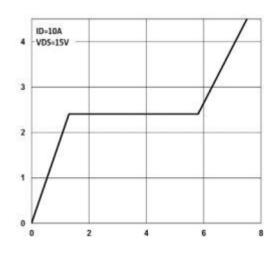
Normalized On Resistance (m^Ω)



T_J, Junction Temperature (°C)

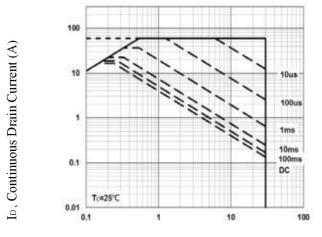
Fig. 2 Normalized RDSON vs. T_J

VGS, Gate to Source Voltage (V)



Qg, Gate Charge (nC)

Fig. 4 Gate Charge Waveform



V_{DS}, Drain to Source Voltage (V)

Fig. 6 Maximum Safe Operation Area

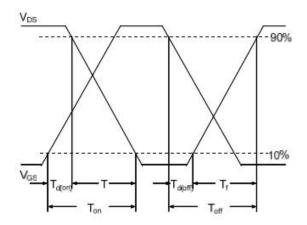
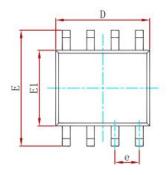
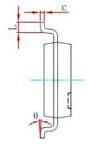


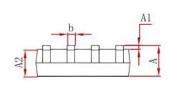
Fig. 7 Switching Time Waveform



PACKAGE MECHANICAL DATA

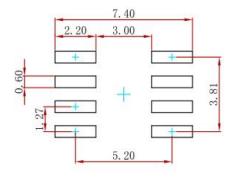






Symbol	Dimensions In	Millimeters	Dimensions	In Inches
Symbol	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0. 100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
с	0. 170	0.250	0.007	0.010
D	4.800	5.000	0.189	0. 197
e	1.270 (BSC)		0.050	(BSC)
Е	5. 800	6.200	0.228	0.244
E1	3.800	4.000	0.150	0.157
L	0.400	1.270	0.016	0.050
θ	0.0	8°	0.0	8°

Suggested Pad Layout



- Note:
 1.Controlling dimension:in millimeters.
 2.General tolerance:±0.05mm.
 3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AO4430	SOP8	3000



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